U.S. P	ATENT DOCUMENTS	<u></u>	
APR 1 0 2009 (Use several sheets if necessary)	FILING DATE January 5, 2006	GROUP 3633	
INFORMATION DISCLOSURE CITATION IN AN APPLICATION	APPLICANT Per Jacobsen		
FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. IPB.021	SERIAL NO. 10/563,422	

RADENA			<u> </u>	PATENT DOCUMENTS			
Examiner Initials		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE if appropriate
	AA.						
	AB.						
	AC.						
	AD.						
	AE.						
	AF.						· · · · · · · · · · · · · · · · · · ·
	AG.					·	

## **FOREIGN PATENT DOCUMENTS**

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translati YES I	ion NO
AH.	JP11-166375	6/22/1999	Japan				
AI.	JP1-168685	11/28/1989	Japan				
AJ.	WO 98/22684	5/28/1998	PCT				•
AK.	JP61-76034	5/22/1986	Japan				
AL.							
AM.							ï

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	AN.	English-language translation of JP61-76034 (2 pa				
	AO.	English-language translation of JP11-166375 (3 pages)				
	AP.	Official Action dated November 18, 2008 of Japanese Patent Application No. 2006-517966 (5 pages)				
EXAMINER			DATE CONSIDERED			

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.

## FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE ATTY. DOCKET NO. SERIAL NO. PATENT AND TRADEMARK OFFICE **IPB.021** 10/563,422 **APPLICANT** INFORMATION DISCLOSURE CITATION Per Jacobsen IN AN APPLICATION **GROUP** (Use several sheets if necessary) FILING DATE 3633 January 5, 2006 **U.S. PATENT DOCUMENTS FILING** Examiner **CLASS** SUBCLASS DATE NAME DATE Initials **DOCUMENT** appropriate NUMBER AQ. AR AS. AT. AU. AV. AW FOREIGN PATENT DOCUMENTS **Translation COUNTRY DOCUMENT NUMBER** DATE **CLASS** SUBCLASS YES NO AX. AY. AZ. OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.) AAA English-language translation (5 pages) of Official Action dated November 18, 2008 of Japanese Patent Application No. 2006-517966 ABE ACC

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.

**EXAMINER** 

DATE CONSIDERED